Search Notes (continued)

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/534,274	HIRANO ET AL.	
Examiner	Art Unit	

2618

Pablo N. Tran

•	

SEARCHED					
Class	Subclass	Date	Examiner		
370	328	07/0/0	7 102		
	903		1		
	203				
	210				
	20%				
	500				
	506				
	506-51	4			
	500				
	500				
	292				
458	6x	1	U		
/			-		
			<del></del>		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	ì			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
(	DATE	EXMR
Baxt Verd	offixlor	L
	, t	
		ŝ